


| | | |
|--|--|---|
| Search Notes  | Application/Control No. 10667368 | Applicant(s)/Patent Under Reexamination NOGUCHI, TAKAFUMI |
| | Examiner Choi, Jacob Y | Art Unit 2885 |

| SEARCHED | | | |
|----------|--|------------|----------|
| Class | Subclass | Date | Examiner |
| 362 | 459, 545, 6, 8, 446, 470, 505, 506, 259, 231 | 10/20/2005 | JC |

| SEARCH NOTES | | |
|--|------------|----------|
| Search Notes | Date | Examiner |
| Class/Subclass & Text Search Conducted by Examiner (including class 359) | 10/20/2005 | JC |
| Updated Search Conducted by Examiner | 8/29/2006 | JC |
| Updated Search Conducted by Examiner | 2/14/2007 | JC |
| STIC Search was performed by M. Mims (e.g., diffracting grating range) | 02/6/2007 | JC |

| INTERFERENCE SEARCH | | | |
|---------------------|----------|------|----------|
| Class | Subclass | Date | Examiner |
| | | | |